



BRF6300 Initialization Script Release Notes

Revision 1.0

January 11, 2007

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Information

Script name BRF6300 1.31 Initialization Script
Filename BRF6300_1.31_P10_26.txt
Version 10.26
Compatibility BRF6300 1.31
Comments Following script support BGA devices.

Contents

Item	LIMITATION - TP/INF/BV-14 Qualification test	
Description	When using the P10_26 initscript, qualification test TP/INF/BV-14 will fail. The upcoming initscript release will include an update for this issue. The failing test verifies that the IUT does not transmit over 4 dbm when features have been exchanged and the Tester does not support RSSI.	
Ref #		P10_26

Item	Power consumption improvement	
Description	Power consumption has been reduced during page and inquiry scan.	
Ref #		P10_26

Item	Class 1.5 reduced power levels	
Description	Support for limiting number of power levels in use. For example: if 3 power levels are used, once device has reached the max / min power level, further increase / decrease requests will return LMP_Max_Power / LMP_Min_Power to peer. Please use the Class 1.5 tool for creation of a Class 1.5 power configuration add-on script.	
Ref #		P10_26

Item	EV3 with Retransmissions during scatternet	
Description	Scatternet scenario: BRF6300 does not accept EV3+Retransmission connection request from slave, when BRF is master in one piconet and slave in active mode in another piconet.	
Ref #		P10_23

Item	Role switch during EV3 + retransmission	
Description	BRF6300 Master to 2 remote peers, one link with active EV3 + retransmission. Device did not accept role switch from remote slave to become master. This issue has been fixed in this service pack.	
Ref #		P10_23

Item	Periodic Inquiry Mode	
Description	Upon issuing HCI_Periodic_Inquiry_Mode, Inquiry starts immediately. Periodic timer starts countdown when first inquiry is completed, beforehand periodic timer started directly after command without initial inquiry.	
Ref #		P10_23

Item	Disconnection of eSCO with retransmission	
Description	BRF6300 is master with eSCO + retransmission link. Host requests eSCO disconnection. Disconnection event is delayed between 5 to 15 seconds. This issue has been fixed in this service pack.	
Ref #		P10_23

Item	ACL Loopback issue with CBT Tester	
Description	During ACL loopback test with Dynamic PRBS payload, BER results are degraded compared to static PRBS ACL loopback measurements. This issue has been fixed in this service pack.	
Ref #		P10_23

Item	SCO creation after UnSniff collision	
Description	SCO connection request fails after UNSNIFF collision. Connection establishment fails with false reason returned to peer device (due to prior collision). This issue has been resolved in the service pack.	

Ref #		P10_18
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Item	Shorter guard time in EDR packets	
Description	Due to a shorter guard time (EDR) on certain BT testers a new vendor specific command has been introduced to control the guard time. Shorter guard time can cause high PER during testmode, failing BT specifications. Please contact your local support representative for more information.	
Ref #		P10_16

Item	Disabling EV3 feature bits	
Description	When disabling EV3 via feature bits, a SCO connection can not be initiated with Setup_Synchronous_Connection command. Issue has been resolved in service pack.	
Ref #		P10_16

Item	HCI_RESET during testmode	
Description	Creation of a new connection fails after issuing HCI_RESET during testmode. Issue has been resolved in service pack. Please note that an Initscript is required to be run after the HCI_RESET command.	
Ref #		P10_16

Item	Unpark failed during LIH-BV-75 qualification test	
Description	Slave failed to initiate un-park during LIH-BV-75 qualification test due to specific park beacon parameters. This issue has been resolved in the service pack.	
Ref #		P10_16

Item	Read_Remote_Extended_Features	
Description	LMP not sent to peer when HOST issues Read_Remote_Extended_Features command. This issue has been resolved in the service pack.	
Ref #		P10_16

Item	LMP_QOS_REQ error code	
Description	Qualification test TP/LIH/BV-41-C. When receiving LMP not accepted from peer in return for LMP_QOS_REQ, device passes to host a success event instead of actual response.	
Ref #		P10_16

Item	LMP_PTT_REQ Collision	
Description	During testmode with EDR feature bits enabled, connection fails with LMP timeout, after LMP_PTT_REQ has been issued from DUT. When EDR feature bits are not enabled issue does not occur. This issue has been resolved in the service pack.	
Ref #		P10_16

Item	DV loopback support	
Description	Test mode DV loopback test fails. This issue has been resolved in the service pack.	
Ref #		P10_16

Item	Power control feature bits	
Description	Device behavior has been changed to allow device to issue power control requests when power control bit is disabled. Power control feature mask operate independently. This issue has been updated in the service pack.	
Ref #		P10_16

Item	EDR relative power	
Description	EDR output power level relative to GFSK has been improved. EDR power has been increased to be approximately equal to GFSK power.	
Ref #		P10_8

Item	Link Supervision Timeout after Role Switch	
Description	During connection with altered link supervision timeout value, a role switch scenario will result in the link supervision timeout value returning to default. Please note that a failing role switch will not return the link supervision timeout to default.	
Ref #		P10_7

Item	RF Improvements	
Description	BER characteristics during EDR have been improved in the current service pack.	
Ref #		P10_7

Item	External FREF default - XTAL Disabled	
Description	The support for external XTAL has been disabled; external FREF configuration will be used as default. Please note that if your design requires an external crystal, XTAL support must be enabled. For more info please see the HCI_VS_Fast_Clock_Configuration Vendor Specific Command.	
Ref #		P10_7

Item	100% PER with Anritsu Bluetooth tester	
Description	During testmode the BRF device sent packets with incorrect access code, causing testing with the Anritsu tester to fail. This issue has been solved in the current service pack.	
Ref #		P10_7

Item	Pin code timeout	
Description	Initial authentication timeout period after entering a wrong pin code has been updated to a 2 second period before a new pin code can be authenticated.	
Ref #		P10_7

Item	Continuous TX during EDR	
Description	The default operation of HCI_VS_DRP_Tester_Continuous_TX during EDR-2 and EDR-3 does not function. Please contact your customer support representative for an appropriate script.	
Ref #		P10_7

Item	Packet type change during authentication	
Description	Host requests authentication, receives a status event and sends a HCI_Change_Connection_Packet_Type command and an HCI_Link_Key_Req event is sent to the host; BRF device does not deliver HCI_Change_Connection_Packet_Type status event to host (BRF waits for the HCI_Link_Key_Response from host), resulting in a host response timeout in the BRF which eventually results in an authentication timeout. This issue is resolved in the current firmware. Please note that the current firmware, on new connection negotiation, creates a link with DH5 enabled, therefore no change packet type command is required.	
Ref #		

Item	AFH during EDR	
Description	Adjusted threshold for bad channel classification during EDR operation.	
Ref #		

Item	CMU ACL loopback	
Description	During testmode scenario with ACL loopback the BRF DUT device returned corrupted packets to CMU Tester, with no payload, containing headers only. This issue has been solved in the current service pack.	
Ref #		

Item	VS_Write_I2C_Register_Enhanced event opcode	
Description	The VS_Write_I2C_Register_Enhanced vendor specific command returns a command complete event with the Opcode of VS_Write_I2C_Register 0xFE0E. To overcome this issue use the following wait command in scripts: Wait_HCI_Command_Complete_Event 5000, any, 0xFE0E, 0x00	
Ref #		

Note: Above changes are firmware bug fixes required by Bluetooth specification and have no effect on previous Bluetooth certification.

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